

Description

The AP15H06S uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

V_{DS} = 60V I_D =15A

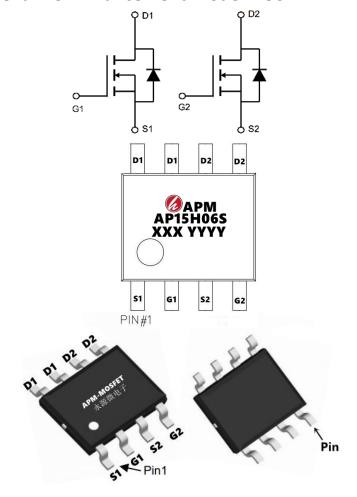
 $R_{DS(ON)} < 18m\Omega$ @ $V_{GS}=10V$ (Type: $11m\Omega$)

Application

Battery protection

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

ackage marking and Ordering information					
Product ID	Pack	Marking	Qty(PCS)		
AP15H06S	SOP-8L	AP15H06S XXX YYYY	3000		

Absolute Maximum Ratings (T_C=25°Cunless otherwise noted)

Symbol	Symbol Parameter		Units	
VDS	Drain-Source Voltage 60		V	
VGS	Gate-Source Voltage	±20	V	
I _D @T _A =25℃	Continuous Drain Current, V _{GS} @ 10V ¹	15	А	
I _D @T _A =70°C	Continuous Drain Current, V _{GS} @ 10V ¹	9.2	А	
IDM	Pulsed Drain Current ²	45	А	
EAS	Single Pulse Avalanche Energy ³	64	mJ	
P _D @T _A =25°C	Total Power Dissipation ⁴	3.6	W	
TSTG	Storage Temperature Range	-55 to 150	$^{\circ}$ C	
TJ	T _J Operating Junction Temperature Range		$^{\circ}$	
R₀JA	Thermal Resistance Junction-Ambient ¹	85	°C/W	





Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit	
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	60	65		V	
∆BVDSS/∆TJ	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =1mA		0.057		V/°C	
DDG(ON)		V _{GS} =10V , I _D =12A		11	18	0	
RDS(ON)	Static Drain-Source On-Resistance ²	V _{GS} =4.5V , I _D =10A		15	20	mΩ	
VGS(th)	Gate Threshold Voltage	V V I 050:A	1.2	1.6	2.5	V	
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	$V_{GS}=V_{DS}$, $I_D=250$ uA		-5.68		mV/°C	
IDCC	Ducin Course Leakens Comment	V _{DS} =48V , V _{GS} =0V , T _J =25°C			1		
IDSS	Drain-Source Leakage Current	V _{DS} =48V , V _{GS} =0V , T _J =55°C		5	- uA		
IGSS	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA	
gfs	Forward Transconductance	V _{DS} =5V , I _D =15A		45		S	
R _g	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		1.7		Ω	
Q _g	Total Gate Charge (4.5V)			19.3			
Q_{gs}	Gate-Source Charge	V _{DS} =48V , V _{GS} =4.5V , I _D =15A		7.1		nC	
Q_{gd}	Gate-Drain Charge			7.6		1	
Td(on)	Turn-On Delay Time			7.2			
T _r	Rise Time	$V_{DD}=30V$, $V_{GS}=10V$, $R_{G}=3.3\Omega$,		50		- ns	
Td(off)	Turn-Off Delay Time	I _D =15A		36.4			
T _f	Fall Time			7.6			
C_{iss}	Input Capacitance			2423			
Coss	Output Capacitance	V _{DS} =15V , V _{GS} =0V , f=1MHz		145		pF	
Crss	Reverse Transfer Capacitance			97			
Is	Continuous Source Current ^{1,5}	V =V =0V Force Current			35	Α	
ISM	Pulsed Source Current ^{2,5}	V _G =V _D =0V , Force Current			80	Α	
VSD	Diode Forward Voltage ²	V _{GS} =0V , I _S =A , T _J =25°C			1	V	
t _{rr}	Reverse Recovery Time	15-154 d1/dt-1004/up T-05°C		16.3		nS	
Q _{rr}	Reverse Recovery Charge	- IF=15A , dI/dt=100A/µs , T _J =25℃		11		nC	

Notes:

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3. The power dissipation is limited by 175 $^{\circ}\mathrm{C}$ junction temperature
- 4. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



Typical Characteristics

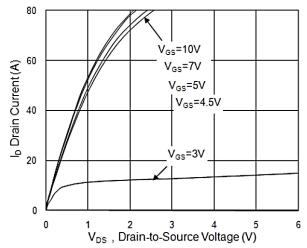


Fig.1 Typical Output Characteristics

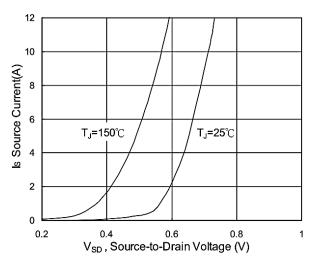


Fig.3 Forward Characteristics of Reverse

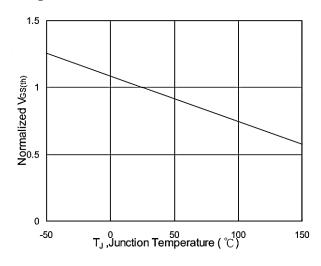


Fig.5 Normalized V_{GS} v.s T_J

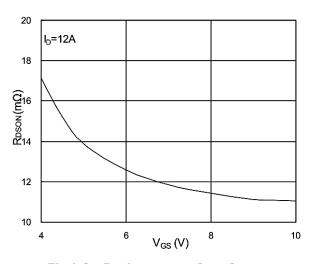


Fig.2 On-Resistance v.s Gate-Source

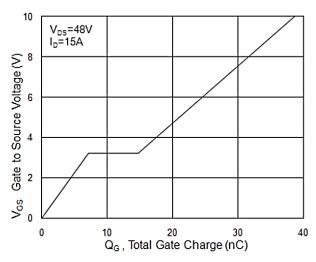


Fig.4 Gate-Charge Characteristics

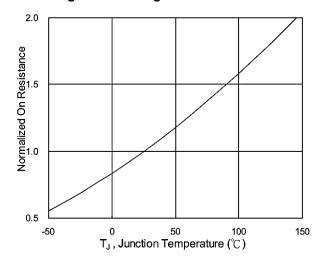
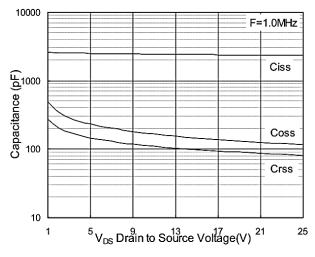


Fig.6 Normalized RDSON v.s TJ







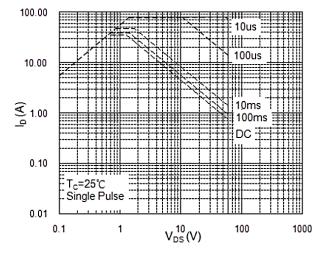


Fig.7 Capacitance

Fig.8 Safe Operating Area

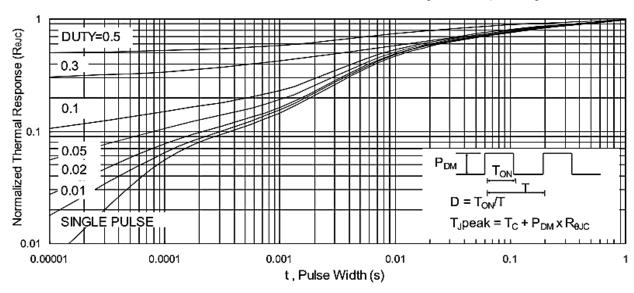


Fig.9 Normalized Maximum Transient Thermal Impedance

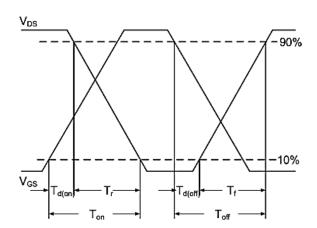


Fig.10 Switching Time Waveform

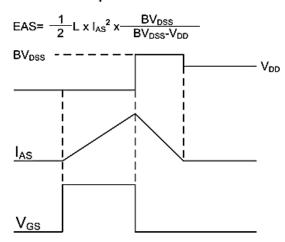
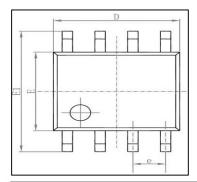
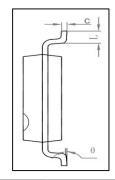


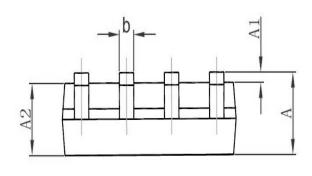
Fig.11 Unclamped Inductive Switching Waveform



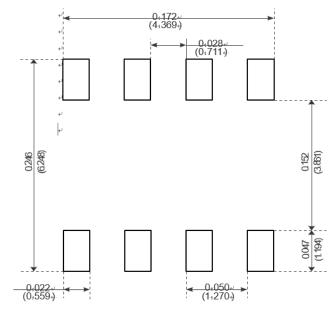
Package Mechanical Data-SOP-8L-DX-Double







Ch - I	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	1. 350	1. 750	0. 053	0.069	
A1	0. 100	0. 250	0. 004	0. 010	
A2	1. 350	1. 550	0. 053	0. 061	
b	0. 330	0. 510	0. 013	0. 020	
С	0. 170	0. 250	0.006	0. 010	
D	4. 700	5. 100	0. 185	0. 200	
E	3. 800	4. 000	0. 150	0. 157	
E1	5. 800	6. 200	0. 228	0. 244	
е	1. 270 (BSC)		0. 050 (BSC)		
L	0. 400	1. 270	0. 016	0.050	
θ	0°	8°	0°	8°	



Recommended Minimum Pads-



Attention

- 1,Any and all APM Microelectronics products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your APM Microelectronics representative nearest you before using any APM Microelectronics products described or contained herein in such applications.
- 2,APM Microelectronics assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all APM Microelectronics products described or contained herein.
- 3, Specifications of any and all APM Microelectronics products described or contained here instipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- 4, APM Microelectronics Semiconductor CO., LTD. strives to supply high quality high reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives that could give rise to smoke or fire, or that could cause damage to other property. Whendesigning equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.
- 5,In the event that any or all APM Microelectronics products (including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.
- 6, No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of APM Microelectronics Semiconductor CO., LTD.
- 7, Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. APM Microelectronics believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.
- 8, Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. When designing equipment, refer to the "Delivery Specification" for the APM Microelectronics product that you Intend to use.





AP15H06S

60V N+N-Channel Enhancement Mode MOSFET

Edition	Date	Change
Rve1.0	2020/12/1	Initial release

Copyright Attribution"APM-Microelectronice"